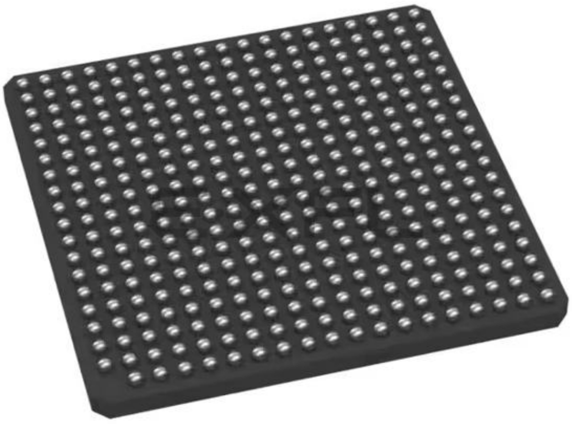
NXP USA Inc. - KMC7448VS1400ND Datasheet



Welcome to **E-XFL.COM**

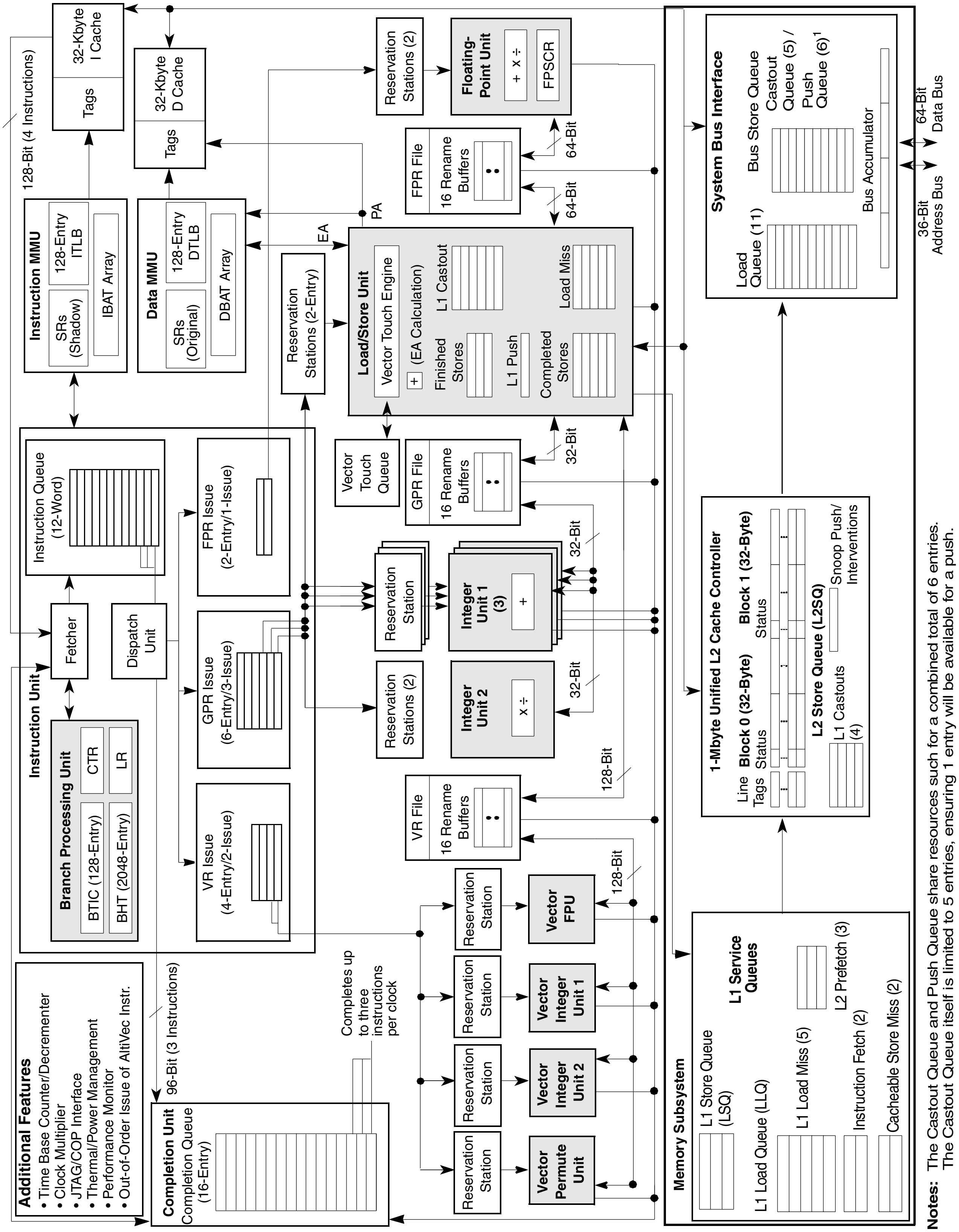
Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC G4
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.4GHz
Co-Processors/DSP	Multimedia; SIMD
RAM Controllers	-
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	-
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	360-CLGA, FCCLGA
Supplier Device Package	360-FCCLGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmc7448vs1400nd



Notes: The Castout Queue and Push Queue share resources such for a combined total of 6 entries. The Castout Queue itself is limited to 5 entries, ensuring 1 entry will be available for a push.

Figure 1. MPC7448 Block Diagram

  - Monitors all dispatched instructions and retires them in order
  - Tracks unresolved branches and flushes instructions after a mispredicted branch
  - Retires as many as three instructions per clock cycle
- Separate on-chip L1 instruction and data caches (Harvard architecture)
  - 32-Kbyte, eight-way set-associative instruction and data caches
  - Pseudo least-recently-used (PLRU) replacement algorithm
  - 32-byte (eight-word) L1 cache block
  - Physically indexed/physical tags
  - Cache write-back or write-through operation programmable on a per-page or per-block basis
  - Instruction cache can provide four instructions per clock cycle; data cache can provide four words per clock cycle
  - Caches can be disabled in software.
  - Caches can be locked in software.
  - MESI data cache coherency maintained in hardware
  - Separate copy of data cache tags for efficient snooping
  - Parity support on cache
  - No snooping of instruction cache except for **icbi** instruction
  - Data cache supports AltiVec LRU and transient instructions
  - Critical double- and/or quad-word forwarding is performed as needed. Critical quad-word forwarding is used for AltiVec loads and instruction fetches. Other accesses use critical double-word forwarding.
- Level 2 (L2) cache interface
  - On-chip, 1-Mbyte, eight-way set-associative unified instruction and data cache
  - Cache write-back or write-through operation programmable on a per-page or per-block basis
  - Parity support on cache tags
  - ECC or parity support on data
  - Error injection allows testing of error recovery software
- Separate memory management units (MMUs) for instructions and data
  - 52-bit virtual address, 32- or 36-bit physical address
  - Address translation for 4-Kbyte pages, variable-sized blocks, and 256-Mbyte segments
  - Memory programmable as write-back/write-through, caching-inhibited/caching-allowed, and memory coherency enforced/memory coherency not enforced on a page or block basis
  - Separate IBATs and DBATs (eight each) also defined as SPRs
  - Separate instruction and data translation lookaside buffers (TLBs)
    - Both TLBs are 128-entry, two-way set-associative and use an LRU replacement algorithm.
    - TLBs are hardware- or software-reloadable (that is, a page table search is performed in hardware or by system software on a TLB miss).

Table 1. Microarchitecture Comparison (continued)

Microarchitectural Specs	MPC7448	MPC7447A	MPC7447	MPC7445	MPC7441
Execution Unit Timings (Latency-Throughput)					
Aligned load (integer, float, vector)	3-1, 4-1, 3-1				
Misaligned load (integer, float, vector)	4-2, 5-2, 4-2				
L1 miss, L2 hit latency with ECC (data/instruction)	12/16	—			
L1 miss, L2 hit latency without ECC (data/instruction)	11/15	9/13			
SFX (add, sub, shift, rot, cmp, logicals)	1-1				
Integer multiply (32 × 8, 32 × 16, 32 × 32)	4-1, 4-1, 5-2				
Scalar float	5-1				
VSFX (vector simple)	1-1				
VCFX (vector complex)	4-1				
VFPU (vector float)	4-1				
VPER (vector permute)	2-1				
MMUs					
TLBs (instruction and data)	128-entry, 2-way				
Tablewalk mechanism	Hardware + software				
Instruction BATs/data BATs	8/8	8/8	8/8	8/8	4/4
L1 I Cache/D Cache Features					
Size	32K/32K				
Associativity	8-way				
Locking granularity	Way				
Parity on I cache	Word				
Parity on D cache	Byte				
Number of D cache misses (load/store)	5/2	5/1			
Data stream touch engines	4 streams				
On-Chip Cache Features					
Cache level	L2				
Size/associativity	1-Mbyte/ 8-way	512-Kbyte/8-way		256-Kbyte/8-way	
Access width	256 bits				
Number of 32-byte sectors/line	2	2			
Parity tag	Byte	Byte			
Parity data	Byte	Byte			
Data ECC	64-bit	—			
Thermal Control					
Dynamic frequency switching divide-by-two mode	Yes	Yes	No	No	No
Dynamic frequency switching divide-by-four mode	Yes	No	No	No	No
Thermal diode	Yes	Yes	No	No	No

Table 6. DC Electrical Specifications (continued)

At recommended operating conditions. See Table 4.

Characteristic		Nominal Bus Voltage [1]	Symbol	Min	Max	Unit	Notes
High-impedance (off-state) leakage current: $V_{in} = OV_{DD}$ V_{in} = GND		—	I_{TSI}	—	 50 – 50	µA	2, 3, 4
Output high voltage @ I_{OH} = –5 mA		1.5	V_{OH}	OV_{DD} – 0.45	—	V	
		1.8		OV_{DD} – 0.45	—		
		2.5		1.8	—		
Output low voltage @ I_{OL} = 5 mA		1.5	V_{OL}	—	0.45	V	
		1.8		—	0.45		
		2.5		—	0.6		
Capacitance, V_{in} = 0 V, f = 1 MHz	All inputs		C_{in}	—	8.0	pF	5

Notes:

1. Nominal voltages; see Table 4 for recommended operating conditions.
2. All I/O signals are referenced to OV_{DD}.
3. Excludes test signals and IEEE Std. 1149.1 boundary scan (JTAG) signals
4. The leakage is measured for nominal OV_{DD} and V_{DD}, or both OV_{DD} and V_{DD} must vary in the same direction (for example, both OV_{DD} and V_{DD} vary by either +5% or –5%).
5. Capacitance is periodically sampled rather than 100% tested.
6. These pins have internal pull-up resistors.

Table 7 provides the power consumption for the MPC7448 part numbers described by this document; see Section 11.1, “Part Numbers Fully Addressed by This Document,” for information regarding which part numbers are described by this document. Freescale also offers MPC7448 part numbers that meet lower power consumption specifications by adhering to lower core voltage and core frequency specifications. For more information on these devices, including references to the MPC7448 Hardware Specification Addenda that describe these devices, see Section 11.2, “Part Numbers Not Fully Addressed by This Document.”

The power consumptions provided in Table 7 represent the power consumption of each speed grade when operated at the rated maximum core frequency (see Table 8). Freescale sorts devices by power as well as by core frequency, and power limits for each speed grade are independent of each other. Each device is tested at its maximum core frequency only. (Note that Deep Sleep Mode power consumption is independent of clock frequency.) Operating a device at a frequency lower than its rated maximum is fully supported provided the clock frequencies are within the specifications given in Table 8, and a device operated below its rated maximum will have lower power consumption. However, inferences should not be made about a device’s power consumption based on the power specifications of another (lower) speed grade. For example, a 1700 MHz device operated at 1420 MHz may not exhibit the same power consumption as a 1420 MHz device operated at 1420 MHz.

For all MPC7448 devices, the following guidelines on the use of these parameters for system design are suggested. The Full-Power Mode–Typical value represents the sustained power consumption of the device when running a typical benchmark at temperatures in a typical system. The Full-Power Mode–Thermal value is intended to represent the sustained power consumption of the device when running a typical code sequence at high temperature and is recommended to be used as the basis for designing a thermal solution; see Section 9.7, "Power and Thermal Management Information" for more information on thermal solutions. The Full-Power Mode–Maximum value is recommended to be used for power supply design because this represents the maximum peak power draw of the device that a power supply must be capable of sourcing without voltage droop. For information on power consumption when dynamic frequency switching is enabled, see Section 9.7.5, "Dynamic Frequency Switching (DFS)."

Table 7. Power Consumption for MPC7448 at Maximum Rated Frequency

	Die Junction Temperature (T_j)	Maximum Processor Core Frequency (Speed Grade, MHz)				Unit	Notes
		1000 MHz	1420 MHz	1600 MHz	1700 MHz		
Full-Power Mode							
Typical	65 •C	15.0	19.0	20.0	21.0	W	1, 2
Thermal	105 •C	18.6	23.3	24.4	25.6	W	1, 5
Maximum	105 •C	21.6	27.1	28.4	29.8	W	1, 3
Nap Mode							
Typical	105 •C	11.1	11.8	13.0	13.0	W	1, 6
Sleep Mode							
Typical	105 •C	10.8	11.4	12.5	12.5	W	1, 6
Deep Sleep Mode (PLL Disabled)							
Typical	105 •C	10.4	11.0	12.0	12.0	W	1, 6

Notes:

1. These values specify the power consumption for the core power supply (V_{DD}) at nominal voltage and apply to all valid processor bus frequencies and configurations. The values do not include I/O supply power (OV_{DD}) or PLL supply power (AV_{DD}). OV_{DD} power is system dependent but is typically < 5% of V_{DD} power. Worst case power consumption for AV_{DD} < 13 mW. Freescale also offers MPC7448 part numbers that meet lower power consumption specifications; for more information on these devices, see Section 11.2, "Part Numbers Not Fully Addressed by This Document."
2. Typical power consumption is an average value measured with the processor operating at its rated maximum processor core frequency (except for Deep Sleep Mode), at nominal recommended V_{DD} (see Table 4) and 65°C while running the Dhrystone 2.1 benchmark and achieving 2.3 Dhrystone MIPs/MHz. This parameter is not 100% tested but periodically sampled.b
3. Maximum power consumption is the average measured with the processor operating at its rated maximum processor core frequency, at nominal V_{DD} and maximum operating junction temperature (see Table 4) while running an entirely cache-resident, contrived sequence of instructions to keep all the execution units maximally busy.
4. Doze mode is not a user-definable state; it is an intermediate state between full-power and either nap or sleep mode. As a result, power consumption for this mode is not tested.
5. Thermal power consumption is an average value measured at the nominal recommended V_{DD} (see Table 4) and 105 °C while running the Dhrystone 2.1 benchmark and achieving 2.3 Dhrystone MIPs/MHz. This parameter is not 100% tested but periodically sampled.
6. Typical power consumption for these modes is measured at the nominal recommended V_{DD} (see Table 4) and 105 °C in the mode described. This parameter is not 100% tested but is periodically sampled.

Table 9. Processor Bus AC Timing Specifications[1] (continued)

At recommended operating conditions. See Table 4.

Parameter	Symbol [2]	All Speed Grades		Unit	Notes
		Min	Max		
SYSCLK to output high impedance (all except $\overline{\text{TS}}$, $\overline{\text{ARTRY}}$, $\overline{\text{SHD0}}$, $\overline{\text{SHD1}}$)	t_{KHOZ}	—	1.8	ns	5
SYSCLK to $\overline{\text{TS}}$ high impedance after precharge	t_{KHTSPZ}	—	1	t_{SYSCLK}	3, 4, 5
Maximum delay to $\overline{\text{ARTRY}}$/$\overline{\text{SHD0}}$/$\overline{\text{SHD1}}$ precharge	t_{KHARP}	—	1	t_{SYSCLK}	3, 5, 6, 7
SYSCLK to $\overline{\text{ARTRY}}$/$\overline{\text{SHD0}}$/$\overline{\text{SHD1}}$ high impedance after precharge	t_{KHARPZ}	—	2	t_{SYSCLK}	3, 5, 6, 7

Notes:

1. All input specifications are measured from the midpoint of the signal in question to the midpoint of the rising edge of the input SYSCLK. All output specifications are measured from the midpoint of the rising edge of SYSCLK to the midpoint of the signal in question. All output timings assume a purely resistive 50-Ω load (see Figure 4). Input and output timings are measured at the pin; time-of-flight delays must be added for trace lengths, vias, and connectors in the system.
2. The symbology used for timing specifications herein follows the pattern of $t_{(signal)(state)(reference)(state)}$ for inputs and $t_{(reference)(state)(signal)(state)}$ for outputs. For example, t_{IVKH} symbolizes the time input signals (I) reach the valid state (V) relative to the SYSCLK reference (K) going to the high (H) state or input setup time. And t_{KHOV} symbolizes the time from SYSCLK(K) going high (H) until outputs (O) are valid (V) or output valid time. Input hold time can be read as the time that the input signal (I) went invalid (X) with respect to the rising clock edge (KH) (note the position of the reference and its state for inputs) and output hold time can be read as the time from the rising edge (KH) until the output went invalid (OX).
3. t_{sysclk} is the period of the external clock (SYSCLK) in ns. The numbers given in the table must be multiplied by the period of SYSCLK to compute the actual time duration (in ns) of the parameter in question.
4. According to the bus protocol, $\overline{\text{TS}}$ is driven only by the currently active bus master. It is asserted low and precharged high before returning to high impedance, as shown in Figure 6. The nominal precharge width for $\overline{\text{TS}}$ is t_{SYSCLK}, that is, one clock period. Since no master can assert $\overline{\text{TS}}$ on the following clock edge, there is no concern regarding contention with the precharge. Output valid and output hold timing is tested for the signal asserted. Output valid time is tested for precharge.The high-impedance behavior is guaranteed by design.
5. Guaranteed by design and not tested
6. According to the bus protocol, $\overline{\text{ARTRY}}$ can be driven by multiple bus masters through the clock period immediately following $\overline{\text{AACK}}$. Bus contention is not an issue because any master asserting $\overline{\text{ARTRY}}$ will be driving it low. Any master asserting it low in the first clock following $\overline{\text{AACK}}$ will then go to high impedance for a fraction of a cycle, then negated for up to an entire cycle (crossing a bus cycle boundary) before being three-stated again. The nominal precharge width for $\overline{\text{ARTRY}}$ is 1.0 t_{SYSCLK}; that is, it should be high impedance as shown in Figure 6 before the first opportunity for another master to assert $\overline{\text{ARTRY}}$. Output valid and output hold timing is tested for the signal asserted.The high-impedance behavior is guaranteed by design.
7. According to the MPX bus protocol, $\overline{\text{SHD0}}$ and $\overline{\text{SHD1}}$ can be driven by multiple bus masters beginning two cycles after $\overline{\text{TS}}$. Timing is the same as $\overline{\text{ARTRY}}$, that is, the signal is high impedance for a fraction of a cycle, then negated for up to an entire cycle (crossing a bus cycle boundary) before being three-stated again. The nominal precharge width for $\overline{\text{SHD0}}$ and $\overline{\text{SHD1}}$ is 1.0 t_{SYSCLK}. The edges of the precharge vary depending on the programmed ratio of core to bus (PLL configurations).
8. $\overline{\text{BMODE}}$[0:1] and BVSEL[0:1] are mode select inputs. $\overline{\text{BMODE}}$[0:1] are sampled before and after $\overline{\text{HRESET}}$ negation. BVSEL[0:1] are sampled before $\overline{\text{HRESET}}$ negation. These parameters represent the input setup and hold times for each sample. These values are guaranteed by design and not tested. $\overline{\text{BMODE}}$[0:1] must remain stable after the second sample; BVSEL[0:1] must remain stable after the first (and only) sample. See Figure 5 for sample timing.

Figure 4 provides the AC test load for the MPC7448.

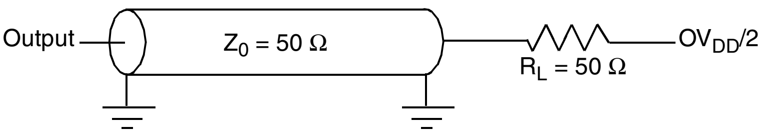


Figure 4. AC Test Load

Figure 5 provides the $\overline{\text{BMODE}}$[0:1] input timing diagram for the MPC7448. These mode select inputs are sampled once before and once after $\overline{\text{HRESET}}$ negation.

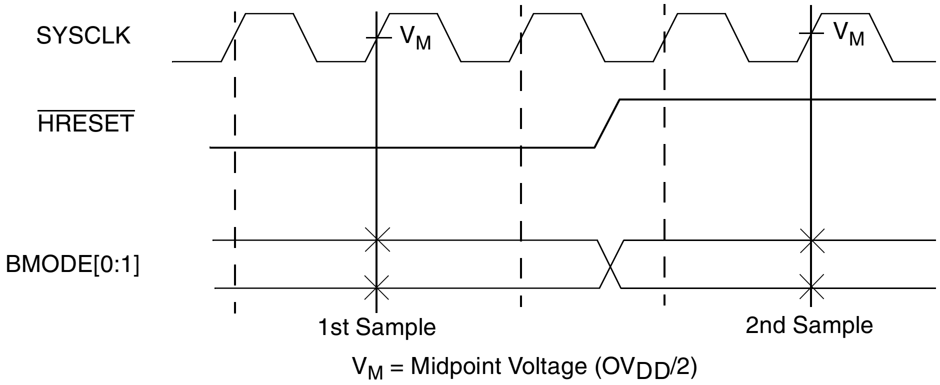


Figure 5. $\overline{\text{BMODE}}$[0:1] Input Sample Timing Diagram

Figure 11 provides the test access port timing diagram.

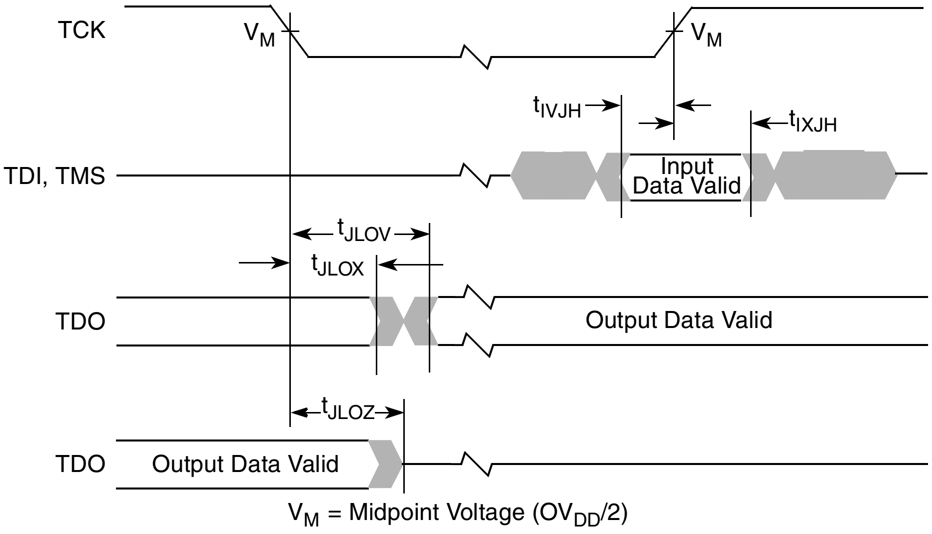


Figure 11. Test Access Port Timing Diagram

5.3 Voltage and Frequency Derating

Voltage and frequency derating is no longer supported for part numbers described by this document beginning with datecode 0613. (See Section 11, "Part Numbering and Marking," for information on date code markings.) It is supported by some MPC7448 part numbers which target low-power applications; see Section 11.2, "Part Numbers Not Fully Addressed by This Document" and the referenced MPC7448 Hardware Specification Addenda for more information on these low-power devices. For those devices which previously supported this feature, information has been archived in the *Chip Errata for the MPC7448* (document order no. MPC7448CE).

Table 11. Pinout Listing for the MPC7448, 360 HCTE Package (continued)

Signal Name	Pin Number	Active	I/O	Notes
$\overline{\text{LVRAM}}$	B10	—	—	12, 20, 22
NC (no connect)	A6, A14, A15, B14, B15, C14, C15, C16, C17, C18, C19, D14, D15, D16, D17, D18, D19, E14, E15, F14, F15, G14, G15, H15, H16, J15, J16, J17, J18, J19, K15, K16, K17, K18, K19, L15, L16, L17, L18, L19	—	—	11
$\overline{\text{LSSD\_MODE}}$	E8	Low	Input	6, 12
$\overline{\text{MCP}}$	C9	Low	Input	
OV$_{DD}$	B4, C2, C12, D5, F2, H3, J5, K2, L5, M3, N6, P2, P8, P11, R4, R13, R16, T6, T9, U2, U12, U16, V4, V7, V10, V14	—	—	
OVDD_SENSE	E18, G18	—	—	16
PLL_CFG[0:4]	B8, C8, C7, D7, A7	High	Input	
PLL_CFG[5]	D10	High	Input	9, 20
$\overline{\text{PMON\_IN}}$	D9	Low	Input	13
$\overline{\text{PMON\_OUT}}$	A9	Low	Output	
$\overline{\text{QACK}}$	G5	Low	Input	
$\overline{\text{QREQ}}$	P4	Low	Output	
$\overline{\text{SHD}}$[0:1]	E4, H5	Low	I/O	3
$\overline{\text{SMI}}$	F9	Low	Input	
$\overline{\text{SRESET}}$	A2	Low	Input	
SYSCLK	A10	—	Input	
$\overline{\text{TA}}$	K6	Low	Input	
TBEN	E1	High	Input	
$\overline{\text{TBST}}$	F11	Low	Output	
TCK	C6	High	Input	
TDI	B9	High	Input	6
TDO	A4	High	Output	
$\overline{\text{TEA}}$	L1	Low	Input	
TEMP_ANODE	N18	—	—	17
TEMP_CATHODE	N19	—	—	17
TMS	F1	High	Input	6
$\overline{\text{TRST}}$	A5	Low	Input	6, 14
$\overline{\text{TS}}$	L4	Low	I/O	3
TSIZ[0:2]	G6, F7, E7	High	Output	
TT[0:4]	E5, E6, F6, E9, C5	High	I/O	
$\overline{\text{WT}}$	D3	Low	Output	
V$_{DD}$	H8, H10, H12, J7, J9, J11, J13, K8, K10, K12, K14, L7, L9, L11, L13, M8, M10, M12	—	—	
V$_{DD}$	A13, A16, A18, B17, B19, C13, E13, E16, F12, F17, F19, G11, G16, H14, H17, H19, M14, M16, M18, N15, N17, P16, P18	—	—	15

8 Package Description

The following sections provide the package parameters and mechanical dimensions for the HCTE package.

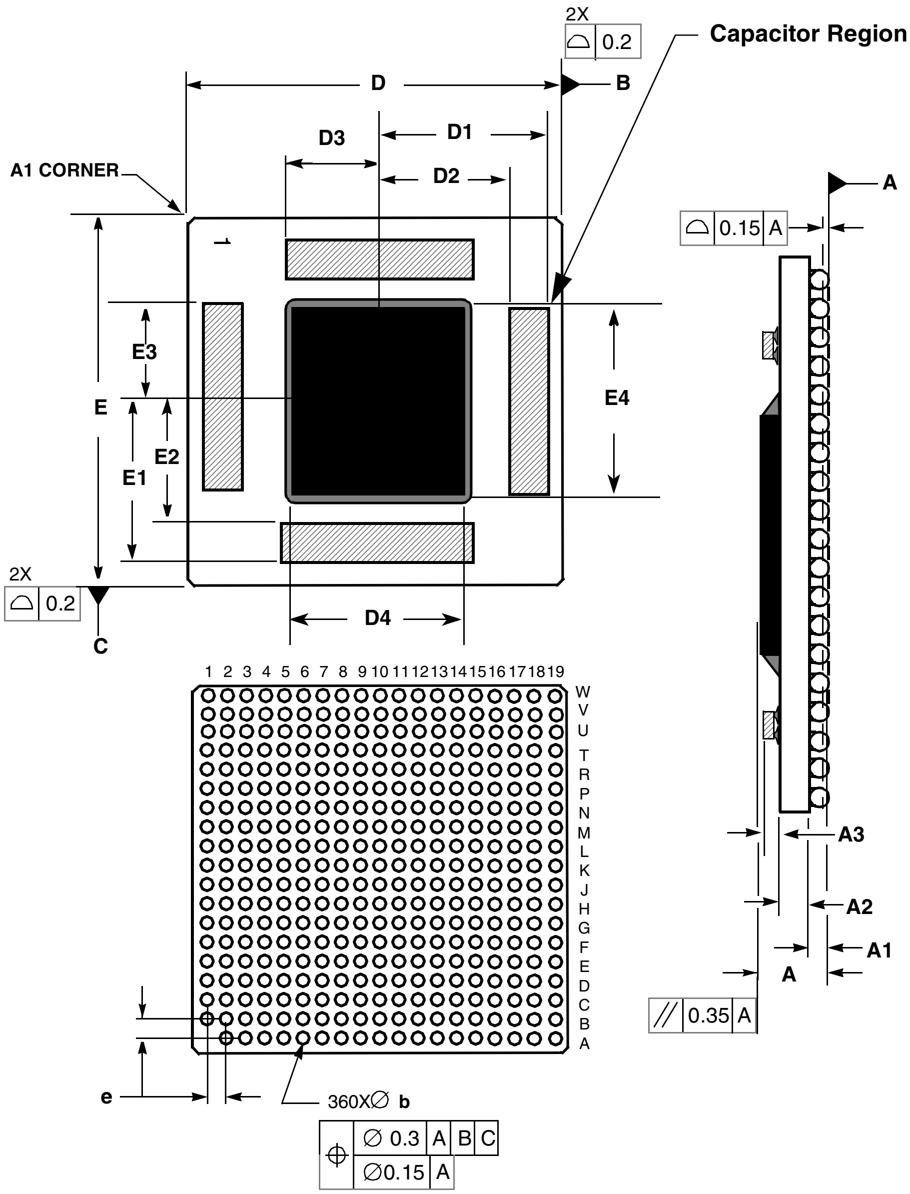
8.1 Package Parameters for the MPC7448, 360 HCTE BGA

The package parameters are as provided in the following list. The package type is 25 × 25 mm, 360-lead high coefficient of thermal expansion ceramic ball grid array (HCTE).

Package outline	25 × 25 mm
Interconnects	360 (19 × 19 ball array – 1)
Pitch	1.27 mm (50 mil)
Minimum module height	2.32 mm
Maximum module height	2.80 mm
Ball diameter	0.89 mm (35 mil)
Coefficient of thermal expansion	12.3 ppm/°C

8.2 Mechanical Dimensions for the MPC7448, 360 HCTE BGA

Figure 13 provides the mechanical dimensions and bottom surface nomenclature for the MPC7448, 360 HCTE BGA package.



NOTES:

1. Dimensioning and tolerancing per ASME Y14.5M, 1994
2. Dimensions in millimeters.
3. Top side A1 corner index is a metalized feature with various shapes. Bottom side A1 corner is designated with a ball missing from the array.

	Millimeters	
Dim	**Min**	**Max**
A	2.32	2.80
A1	0.80	1.00
A2	0.70	0.90
A3	—	0.6
b	0.82	0.93
D	25.00 BSC	
D1	—	11.3
D2	8.0	—
D3	—	6.5
D4	7.2	7.4
e	1.27 BSC	
E	25.00 BSC	
E1	—	11.3
E2	8.0	—
E3	—	6.5
E4	7.9	8.1

Figure 13. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC7448, 360 HCTE BGA Package

Table 12. MPC7448 Microprocessor PLL Configuration Example (continued)

PLL_CFG[0:5]	Example Core and VCO Frequency in MHz										
	Bus-to-Core Multiplier [5]	Core-to-VCO Multiplier [5]	Bus (SYSCLK) Frequency								
			33.3 MHz	50 MHz	66.6 MHz	75 MHz	83 MHz	100 MHz	133 MHz	167 MHz	200 MHz
100110	11x	1x			733	825	913	1100	1467		
000000	11.5x	1x			766	863	955	1150	1533		
101110	12x	1x		600	800	900	996	1200	1600		
111110	12.5x	1x		625	833	938	1038	1250	1667		
010110	13x	1x		650	865	975	1079	1300			
111000	13.5x	1x		675	900	1013	1121	1350			
110010	14x	1x		700	933	1050	1162	1400			
000110	15x	1x		750	1000	1125	1245	1500			
110110	16x	1x		800	1066	1200	1328	1600			
000010	17x	1x		850	1132	1275	1417	1700			
001010	18x	1x	600	900	1200	1350	1500				
001110	20x	1x	667	1000	1332	1500	1666				
010010	21x	1x	700	1050	1399	1575					
011010	24x	1x	800	1200	1600						
111010	28x	1x	933	1400							
001100	PLL bypass		PLL off, SYSCLK clocks core circuitry directly								
111100	PLL off		PLL off, no core clocking occurs								

Notes:

1. PLL_CFG[0:5] settings not listed are reserved.
2. The sample bus-to-core frequencies shown are for reference only. Some PLL configurations may select bus, core, or VCO frequencies which are not useful, not supported, or not tested for by the MPC7448; see Section 5.2.1, "Clock AC Specifications," for valid SYSCLK, core, and VCO frequencies.
3. In PLL-bypass mode, the SYSCLK input signal clocks the internal processor directly and the PLL is disabled. However, the bus interface unit requires a 2x clock to function. Therefore, an additional signal, EXT_QUAL, must be driven at half the frequency of SYSCLK and offset in phase to meet the required input setup t_{IVKH} and hold time t_{IXKH} (see Table 9). The result will be that the processor bus frequency will be one-half SYSCLK, while the internal processor is clocked at SYSCLK frequency. This mode is intended for factory use and emulator tool use only.
   Note: The AC timing specifications given in this document do not apply in PLL-bypass mode.
4. In PLL-off mode, no clocking occurs inside the MPC7448 regardless of the SYSCLK input.
5. Applicable when DFS modes are disabled. These multipliers change when operating in a DFS mode. See Section 9.7.5, "Dynamic Frequency Switching (DFS)" for more information.
6. Bus-to-core multipliers less than 5x require that assertion of AACK be delayed by one or two bus cycles to allow the processor to generate a response to a snooped transaction. See the *MPC7450 RISC Microprocessor Reference Manual* for more information.

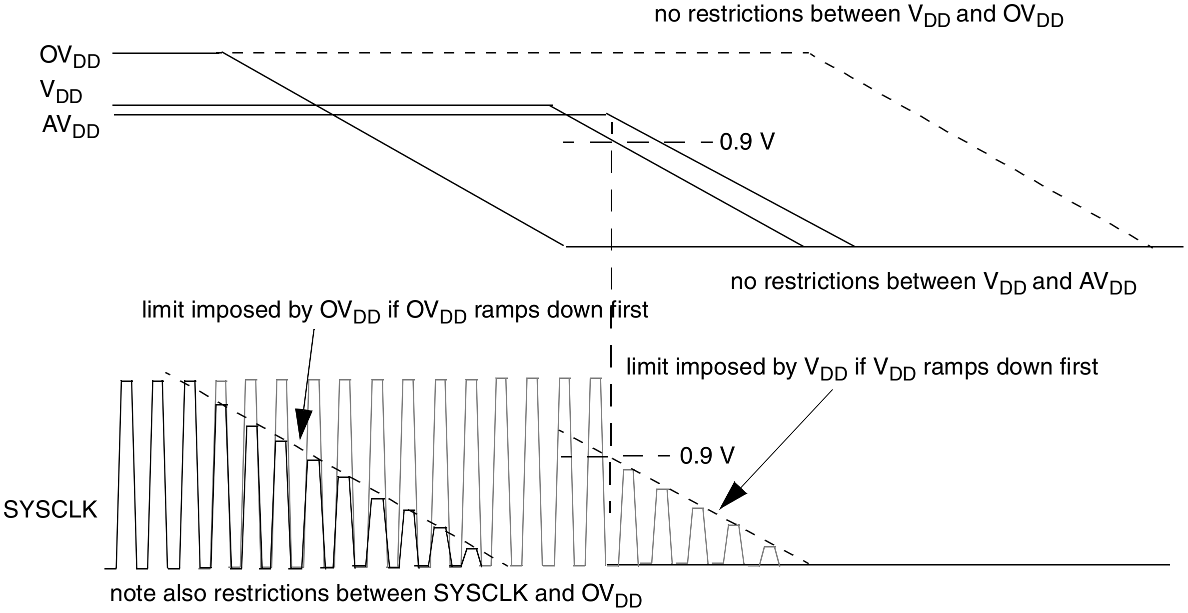


Figure 17. MPC7448 Power Down Sequencing Requirements

There is no requirement regarding AV_{DD} during power down, but it is recommended that AV_{DD} track V_{DD} within the RC time constant of the PLL filter circuit described in Section 9.2.2, “PLL Power Supply Filtering” (nominally 100 µs).

9.2.2 PLL Power Supply Filtering

The AV_{DD} power signal is provided on the MPC7448 to provide power to the clock generation PLL. To ensure stability of the internal clock, the power supplied to the AV_{DD} input signal should be filtered of any noise in the 500-KHz to 10-MHz resonant frequency range of the PLL. The circuit shown in Figure 18 using surface mount capacitors with minimum effective series inductance (ESL) is strongly recommended. In addition to filtering noise from the AV_{DD} input, it also provides the required delay between V_{DD} and AV_{DD} as described in Section 9.2.1, “Power Supply Sequencing.”

The circuit should be placed as close as possible to the AV_{DD} pin to minimize noise coupled from nearby circuits. It is often possible to route directly from the capacitors to the AV_{DD} pin, which is on the periphery of the device footprint.

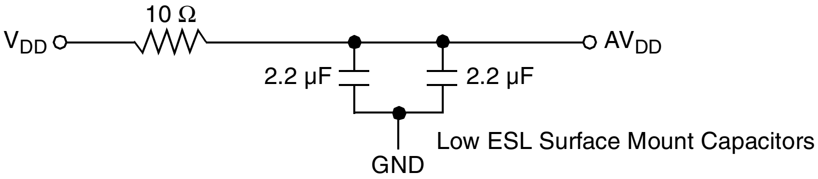
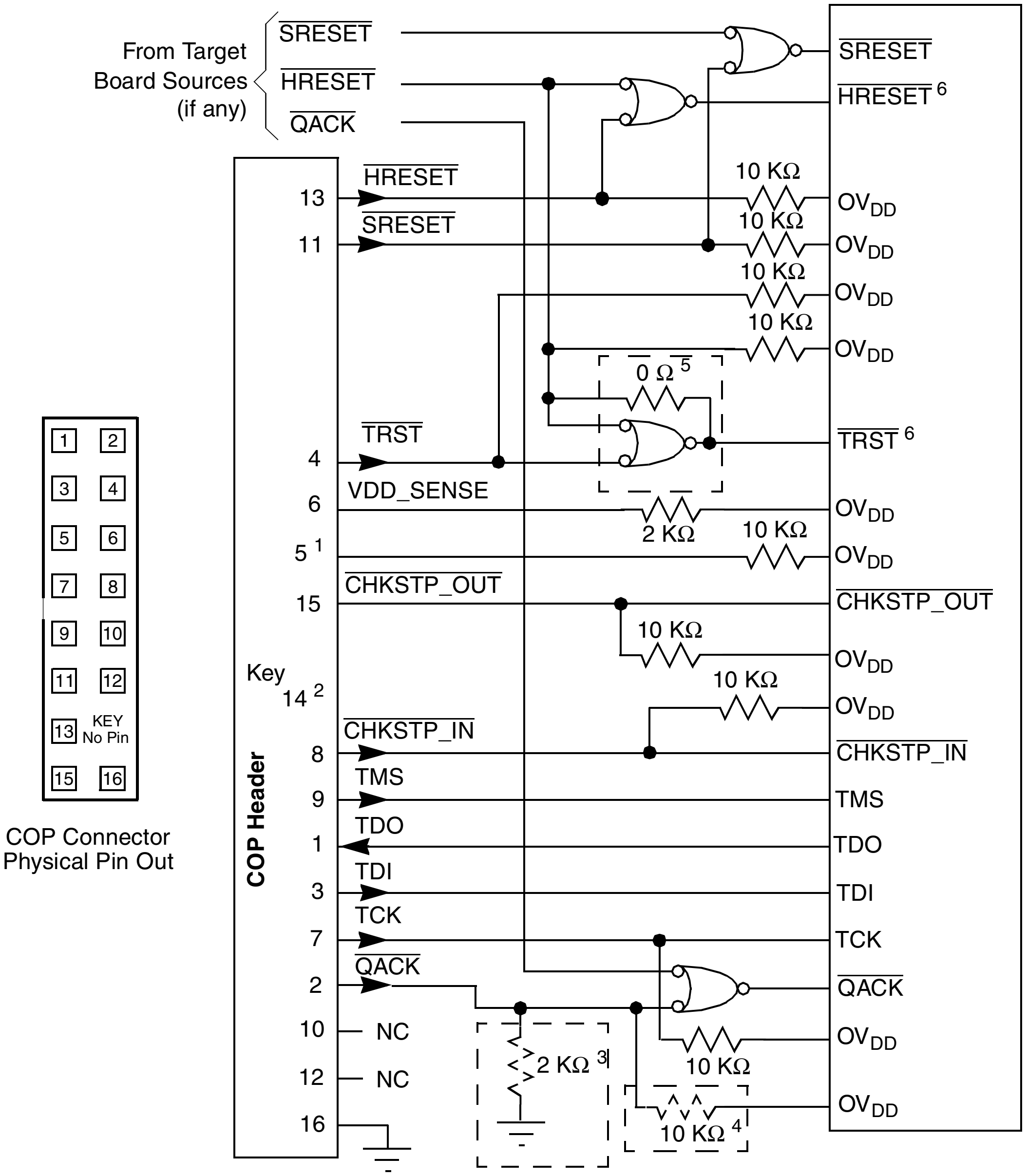


Figure 18. PLL Power Supply Filter Circuit



Notes:

1. RUN/$\overline{\text{STOP}}$, normally found on pin 5 of the COP header, is not implemented on the MPC7448. Connect pin 5 of the COP header to OV_{DD} with a 10-KΩ pull-up resistor.
2. Key location; pin 14 is not physically present on the COP header.
3. Component not populated. Populate only if debug tool does not drive $\overline{\text{QACK}}$.
4. Populate only if debug tool uses an open-drain type output and does not actively negate $\overline{\text{QACK}}$.
5. If the JTAG interface is implemented, connect $\overline{\text{HRESET}}$ from the target source to $\overline{\text{TRST}}$ from the COP header though an AND gate to $\overline{\text{TRST}}$ of the part. If the JTAG interface is not implemented, connect $\overline{\text{HRESET}}$ from the target source to $\overline{\text{TRST}}$ of the part through a 0-Ω isolation resistor.
6. The COP port and target board should be able to independently assert $\overline{\text{HRESET}}$ and $\overline{\text{TRST}}$ to the processor in order to fully control the processor as shown above.

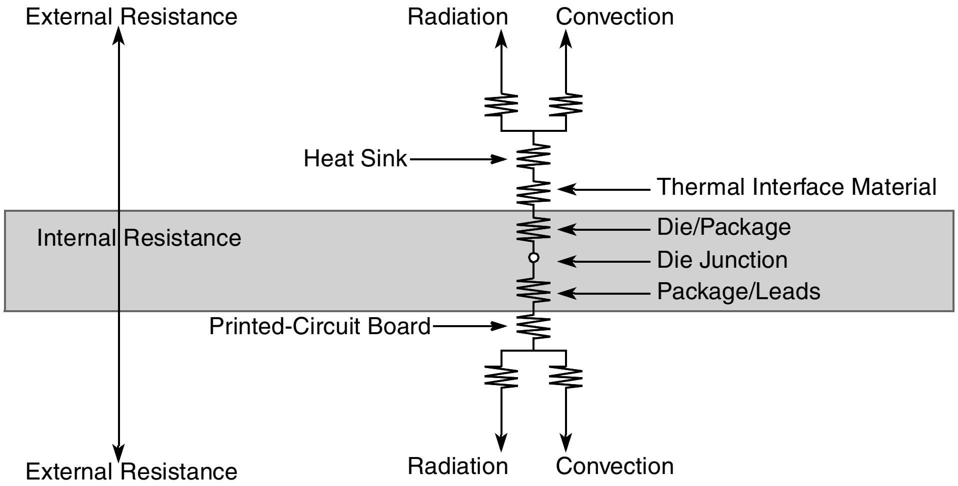
Figure 21. JTAG Interface Connection

9.7.1 Internal Package Conduction Resistance

For the exposed-die packaging technology described in Table 5, the intrinsic conduction thermal resistance paths are as follows:

- The die junction-to-case thermal resistance (the case is actually the top of the exposed silicon die)
- The die junction-to-board thermal resistance

Figure 24 depicts the primary heat transfer path for a package with an attached heat sink mounted to a printed-circuit board.



(Note the internal versus external package resistance.)

Figure 24. C4 Package with Heat Sink Mounted to a Printed-Circuit Board

Heat generated on the active side of the chip is conducted through the silicon, through the heat sink attach material (or thermal interface material), and, finally, to the heat sink, where it is removed by forced-air convection.

Because the silicon thermal resistance is quite small, the temperature drop in the silicon may be neglected for a first-order analysis. Thus, the thermal interface material and the heat sink conduction/convective thermal resistances are the dominant terms.

9.7.2 Thermal Interface Materials

A thermal interface material is recommended at the package lid-to-heat sink interface to minimize the thermal contact resistance. For those applications where the heat sink is attached by spring clip mechanism, Figure 25 shows the thermal performance of three thin-sheet thermal-interface materials (silicone, graphite/oil, fluoroether oil), a bare joint, and a joint with thermal grease as a function of contact pressure. As shown, the performance of these thermal interface materials improves with increasing contact pressure. The use of thermal grease significantly reduces the interface thermal resistance. That is, the bare joint results in a thermal resistance approximately seven times greater than the thermal grease joint.

Often, heat sinks are attached to the package by means of a spring clip to holes in the printed-circuit board (see Figure 22). Therefore, synthetic grease offers the best thermal performance due to the low interface pressure and is recommended due to the high power dissipation of the MPC7448. Of course, the selection

Shin-Etsu MicroSi, Inc. 10028 S. 51st St. Phoenix, AZ 85044 Internet: www.microsi.com	888-642-7674
Laird Technologies - Thermal (formerly Thermagon Inc.) 4707 Detroit Ave. Cleveland, OH 44102 Internet: www.lairdtech.com	888-246-905

The following section provides a heat sink selection example using one of the commercially available heat sinks.

9.7.3 Heat Sink Selection Example

For preliminary heat sink sizing, the die-junction temperature can be expressed as follows:

$$T_j = T_i + T_r + (R_{\theta JC} + R_{\theta int} + R_{\theta sa}) \times P_d$$

where:

T_j is the die-junction temperature
T_i is the inlet cabinet ambient temperature
T_r is the air temperature rise within the computer cabinet
$R_{\theta JC}$ is the junction-to-case thermal resistance
$R_{\theta int}$ is the adhesive or interface material thermal resistance
$R_{\theta sa}$ is the heat sink base-to-ambient thermal resistance
P_d is the power dissipated by the device

During operation, the die-junction temperatures (T_j) should be maintained less than the value specified in Table 4. The temperature of air cooling the component greatly depends on the ambient inlet air temperature and the air temperature rise within the electronic cabinet. An electronic cabinet inlet-air temperature (T_i) may range from 30□ to 40□C. The air temperature rise within a cabinet (T_r) may be in the range of 5□ to 10□C. The thermal resistance of the thermal interface material ($R_{\theta int}$) is typically about 1.1 □C/W. For example, assuming a T_i of 30□C, a T_r of 5□C, an HCTE package $R_{\theta JC}$ = 0.1, and a power consumption (P_d) of 25.6 W, the following expression for T_j is obtained:

Die-junction temperature: $T_j = 30\square C + 5\square C + (0.1\square C/W + 1.1\square C/W + \theta_{sa}) \times 25.6$

For this example, a $R_{\theta sa}$value of 1.53 □C/W or less is required to maintain the die junction temperature below the maximum value of Table 4.

Though the die junction-to-ambient and the heat sink-to-ambient thermal resistances are a common figure-of-merit used for comparing the thermal performance of various microelectronic packaging technologies, one should exercise caution when only using this metric in determining thermal management because no single parameter can adequately describe three-dimensional heat flow. The final die-junction operating temperature is not only a function of the component-level thermal resistance, but the system-level design and its operating conditions. In addition to the component's power consumption, a number of factors affect the final operating die-junction temperature—airflow, board population (local heat flux of adjacent components), heat sink efficiency, heat sink attach, heat sink placement, next-level interconnect technology, system air temperature rise, altitude, and so on.

Table 16. Valid Divide Ratio Configurations (continued)

DFS mode disabled		DFS divide-by-2 mode enabled (HID1[DFS2] = 1 or $\overline{\text{DFS2}}$ = 0)		DFS divide-by-4 mode enabled (HID1[DFS4] = 1 or $\overline{\text{DFS4}}$ = 0)	
Bus-to-Core Multiplier Configured by PLL_CFG[0:5] (see Table 12)	HID1[PC0-5] [3]	Bus-to-Core Multiplier	HID1[PC0-5] [3]	Bus-to-Core Multiplier	HID1[PC0-5] [3]
24x	011010	12x	101110	6x	110100
28x	111010	14x	110010	7x	001000

Notes:

1. DFS mode is not supported for this combination of DFS mode and PLL_CFG[0:5] setting. As a result, the processor will ignore these settings and remain at the previous multiplier, as reflected by the HID1[PC0-PC5] bits.
2. Though supported by the MPC7448 clock circuitry, multipliers of *n*.25x and *n*.75x cannot be expressed as valid PLL configuration codes. As a result, the values displayed in HID1[PC0-PC5] are rounded down to the nearest valid PLL configuration code. However, the actual bus-to-core multiplier is as stated in this table.
3. Note that in the HID1 register of the MPC7448, the PC0, PC1, PC2, PC3, PC4, and PC5 bits are bits 15, 16, 17, 18, 19, and 14 (respectively). See the *MPC7450 RISC Microprocessor Reference Manual* for more information.
4. Special considerations regarding snooped transactions must be observed for bus-to-core multipliers less than 5x. See the *MPC7450 RISC Microprocessor Reference Manual* for more information.

9.7.5.3 Minimum Core Frequency Requirements with DFS

In many systems, enabling DFS can result in very low processor core frequencies. However, care must be taken to ensure that the resulting processor core frequency is within the limits specified in Table 8. Proper operation of the device is not guaranteed at core frequencies below the specified minimum f_{core}.

10 Document Revision History

Table 17 provides a revision history for this hardware specification.

Table 17. Document Revision History

Revision	Date	Substantive Change(s)
4	3/2007	Table 19: Added 800 MHz processor frequency.
3	10/2006	Section 9.7, “Power and Thermal Management Information”: Updated contact information. Table 18, Table 20, and Table 19: Added Revision D PVR. Table 19: Added 600 processor frequency, additional product codes, date codes for 1400 processor frequency, and footnotes 1 and 2. Table 20: Added PPC product code and footnote 1. Table 19 and Table 20: Added Revision D information for 1267 processor frequency.

11 Part Numbering and Marking

Ordering information for the part numbers fully covered by this specification document is provided in Section 11.1, “Part Numbers Fully Addressed by This Document.” Note that the individual part numbers correspond to a maximum processor core frequency. For available frequencies, contact a local Freescale sales office. In addition to the processor frequency, the part numbering scheme also includes an application modifier that may specify special application conditions. An optional specification modifier may also apply for parts to indicate a specific change in specifications, such as support for an extended temperature range. Finally, each part number contains a revision level code that refers to the die mask revision number. Section 11.2, “Part Numbers Not Fully Addressed by This Document,” lists the part numbers that do not fully conform to the specifications of this document. These special part numbers require an additional document called a hardware specification addendum.

11.1 Part Numbers Fully Addressed by This Document

Table 18 provides the Freescale part numbering nomenclature for the MPC7448 part numbers fully addressed by this document. For information regarding other MPC7448 part numbers, see Section 11.2, “Part Numbers Not Fully Addressed by This Document.”

Table 18. Part Numbering Nomenclature

xx	**7448**	***xx***	***nnnn***	**L**	***x***
Product Code	**Part Identifier**	**Package**	**Processor Frequency**	**Application Modifier**	**Revision Level**
MC PPC [1]	7448	HX = HCTE BGA VS = RoHS LGA VU = RoHS BGA	1700	L: 1.3 V +20/–50 mV 0 to 105 °C	C: 2.1; PVR = 0x8004_0201 D: 2.2; PVR = 0x8004_0202
			1600	L: 1.25 V ± 50 mV 0 to 105 °C	
			1420	L: 1.2 V ± 50 mV 0 to 105 °C	
			1000	L: 1.15 V ± 50 mV 0 to 105 °C	

Notes:

1. The P prefix in a Freescale part number designates a “Pilot Production Prototype” as defined by Freescale SOP 3-13. These parts have only preliminary reliability and characterization data. Before pilot production prototypes may be shipped, written authorization from the customer must be on file in the applicable sales office acknowledging the qualification status and the fact that product changes may still occur as pilot production prototypes are shipped.

Table 20. Part Numbers Addressed by MC7448T*xxnnnn*N*x* Series Hardware Specification Addendum (Document Order No. MPC7448ECS02AD)

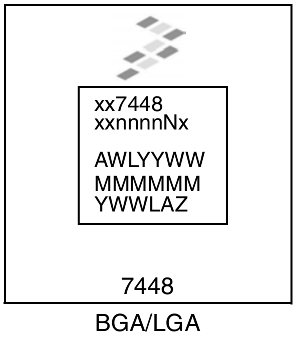
xx	**7448**	**T**	***xx***	***nnnn***	**N**	***x***
Product Code	**Part Identifier**	**Specification Modifier**	**Package**	**Processor Frequency**	**Application Modifier**	**Revision Level**
MC PPC[1]	7448	T = Extended Temperature Device	HX = HCTE BGA	1400	N: 1.15 V ± 50 mV – 40 to 105 °C	C: 2.1; PVR = 0x8004_0201 D: 2.2; PVR = 0x8004_0202
				1267 Revision C only	N: 1.1 V ± 50 mV – 40 to 105 °C	
				1267 Revision D only	N: 1.05 V ± 50 mV – 40 to 105 °C	
				1000	N: 1.0 V ± 50 mV – 40 to 105 °C	

Notes:

1. The P prefix in a Freescale part number designates a “Pilot Production Prototype” as defined by Freescale SOP 3-13. These parts have only preliminary reliability and characterization data. Before pilot production prototypes can be shipped, written authorization from the customer must be on file in the applicable sales office acknowledging the qualification status and the fact that product changes may still occur as pilot production prototypes are shipped.

11.3 Part Marking

Parts are marked as the example shown in Figure 27.



Notes:

AWLYYWW is the test code, where YYWW is the date code (YY = year, WW = work week)
MMMMMM is the M00 (mask) number.
YWWLAZ is the assembly traceability code.

Figure 27. Part Marking for BGA and LGA Device

How to Reach Us:

Home Page:
www.freescale.com

email:
support@freescale.com

USA/Europe or Locations Not Listed:
Freescale Semiconductor
Technical Information Center, CH370
1300 N. Alma School Road
Chandler, Arizona 85224
1-800-521-6274
480-768-2130
support@freescale.com

Europe, Middle East, and Africa:
Freescale Halbleiter Deutschland GmbH
Technical Information Center
Schatzbogen 7
81829 Muenchen, Germany
+44 1296 380 456 (English)
+46 8 52200080 (English)
+49 89 92103 559 (German)
+33 1 69 35 48 48 (French)
support@freescale.com

Japan:
Freescale Semiconductor Japan Ltd.
Headquarters
ARCO Tower 15F
1-8-1, Shimo-Meguro, Meguro-ku
Tokyo 153-0064, Japan
0120 191014
+81 3 5437 9125
support.japan@freescale.com

Asia/Pacific:
Freescale Semiconductor Hong Kong Ltd.
Technical Information Center
2 Dai King Street
Tai Po Industrial Estate,
Tai Po, N.T., Hong Kong
+800 2666 8080
support.asia@freescale.com

For Literature Requests Only:
Freescale Semiconductor
Literature Distribution Center
P.O. Box 5405
Denver, Colorado 80217
1-800-441-2447
303-675-2140
Fax: 303-675-2150
LDCForFreescaleSemiconductor
@hibbertgroup.com

Information in this document is provided solely to enable system and software implementers to use Freescale Semiconductor products. There are no express or implied copyright licenses granted hereunder to design or fabricate any integrated circuits or integrated circuits based on the information in this document.

Freescale Semiconductor reserves the right to make changes without further notice to any products herein. Freescale Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does Freescale Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages. “Typical” parameters which may be provided in Freescale Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including “Typicals” must be validated for each customer application by customer’s technical experts. Freescale Semiconductor does not convey any license under its patent rights nor the rights of others. Freescale Semiconductor products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the Freescale Semiconductor product could create a situation where personal injury or death may occur. Should Buyer purchase or use Freescale Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold Freescale Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that Freescale Semiconductor was negligent regarding the design or manufacture of the part.

Freescale™ and the Freescale logo are trademarks of Freescale Semiconductor, Inc. The Power Architecture and Power.org word marks and the Power and Power.org logos and related marks are trademarks and service marks licensed by Power.org. The described product is a PowerPC microprocessor. The PowerPC name is a trademark of IBM Corp. and is used under license. IEEE Stds. 1149.1™ and 754™ are trademarks of the Institute of Electrical and Electronics Engineers, Inc., (IEEE). This product is not endosed or approved by the IEEE. All other product or service names are the property of their respective owners.

© Freescale Semiconductor, Inc., 2005, 2007.

Document Number: MPC7448EC
Rev. 4
3/2007